

Form PTO-1449	U.S. Dept. of Commerce Patent & Trademark Office	Atty. Docket: POU920010019US1	Serial No. (not yet assigned)
List of Documents Cited by Applicant (Use several sheets if necessary)		Applicant: Jason D. HIBBELER et al.	
		Filing Date: Herewith	2124 Group: (not yet assigned)

U.S. PATENT DOCUMENTS

Ex'r's In'l		Document Number	Date	Name	Class	Sub- class	Filing Date, if applicable
CD	AA1	5,121,501	June 9, 1992	Baumgartner, et al.			
CD	AA2	5,347,649	September 13, 1994	Alderson			
CD	AA3	5,355,487	October 11, 1994	Keller, et al.			
CD	AA4	5,446,876	August 29, 1995	Levine, et al.			
CD	AA5	5,594,864	January 14, 1997	Trauben			
CD	AA6	5,664,095	September 2, 1997	Cox, et al.			
CD	AA7	5,761,091	June 2, 1998	Agrawal, et al.			
CD	AA8	5,797,115	August 18, 1998	Fuller			
CD	AA9	5,964,893	October 12, 1999	Circello, et al.			
CD	AB1	6,086,618	July 11, 2000	Al-Hilali, et al.			

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Sub- class	Trans'n Yes/No
CD	AB2	JP6342386A	September 2, 1992	Japan			Yes (Abstract)

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

CD	AB3	IBM Technical Disclosure Bulletin, "Processor Architecture for Measurement and Monitoring Functions," Vol. 32, No. 9A, February 1990.					
CD	AB4	IBM Technical Disclosure Bulletin, "Process for Real-Time, Trace-Driven Performance Monitors," Vol. 34, No. 5, October 1991.					
CD	AB5	IBM Technical Disclosure Bulletin, "Programmable Performance Monitor Apparatus for a Multi-Chip Super Scalar Processor, Vol. 37, No. 04B, April 1994.					
CD	AB6	IBM Research Disclosure No. 42898, "Automated Inclusion of Program Tracing Statements," December 1999.					
CD	AB7	IBM Research Disclosure No. 431, "Dynamic Monitoring of System Parameters," March 2000.					

Examiner:

Carlene Gordon

Date Considered:

09/15/04

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.